

Application No.	Applicant(s)
09/802,464	BAWOLEK ET AL.
Examiner	Art Unit
Insé P. Díaz	2815

	SEARCHED				
Class	Subclass	Date	Examiner		
257	434, 435, 440, 443, 448, 457	7/20/2004	JRD		
257	459	7/20/2004	JRD		
		,			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Discussed with Tom Thomas	7/15/2004	JRD		
Discussed with Bill Baumeister 257/434,435,440,443,448,457,459 (photo-diode, light detector, photo- detector,	7/20/2004	JRD		
p-i-n or pin diode, and pixel) in combination with (area, size geometry shape, opening)	7/20/2004	JRD		
Text Search: East (see attachment)	7/20/2004	JRD		